

A benchmark suite for evaluating the efficiency of test tools

Kruus, Helena; Ubar, Raimund-Johannes; Ellervee, Peeter; Gorev, Maksim; Pesonen, Vadim; Devadze, Sergei; Orasson, Elmet; Brik, Marina; Min, Mart; Annus, Paul; Kruus, Margus; Meigas, Kalju BEC 2012 : 2012 13th Biennial Baltic Electronics Conference : proceedings of the 13th Biennial Baltic Electronics Conference : October 3-5, 2012, Tallinn, Estonia 2012 / p. 85-88 : ill

Combining learning, training and research in laboratory course for design and test

Ubar, Raimund-Johannes; Orasson, Elmet; Raik, Jaan; Wuttke, Heinz-Dietrich The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 221-224 : ill
https://www.researchgate.net/publication/242397131_Combining_Learning_Training_and_Research_in_Laboratory_Course_for_Design_and_Test

Diagnostic software with WEB interface for teaching purposes

Vislogubov, Vladislav; Jutman, Artur; Kruus, Helena; Orasson, Elmet; Raik, Jaan; Ubar, Raimund-Johannes BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 255-258 : ill

Double phase fault collapsing with linear complexity in digital circuits

Ubar, Raimund-Johannes; Jürimägi, Lembit; Orasson, Elmet; Josifovska, Galina; Oyeniran, Adeboye Stephen DSD 2015 : 18th Euromicro Conference on Digital Systems Design : 26-28 August 2015, Funchal, Madeira, Portugal 2015 / p. 700-705 : ill

E-learning environment for WEB-based study of testing

Ubar, Raimund-Johannes; Jutman, Artur; Raik, Jaan; Devadze, Sergei; Jenihhin, Maksim; Aleksejev, Igor; Tšepurov, Anton; Tšertov, Anton; Kostin, Sergei; Orasson, Elmet; Wuttke, Heinz-Dietrich Proceedings of the 8th European Workshop on Microelectronics Education : EWME 2010 : Darmstadt, Germany, 10-12 May 2010 2010 / p. 47-52 : ill

E-learning tool and exercises for teaching digital test

Ubar, Raimund-Johannes; Orasson, Elmet Proceedings of the 2nd IEEE Conference on Signals, Systems, Decision and Information Technology : Sousse, Tunisia, 2003 2003 / [6] p. : ill <https://pld.ttu.ee/dildis/publications/E-Learning%20tool%20and%20Exercises.pdf>

E-learning tool and exercises for teaching digital test

Ubar, Raimund-Johannes; Orasson, Elmet Proceedings of the 2nd IEEE Conference on Signals, Systems, Decision and Information Technology : Sousse, Tunisia, 2003 : summaries / p. 134

E-learning tools for digital test

Devadze, Sergei; Gorjachev, R.; Jutman, Artur; Orasson, Elmet; Rosin, Vjatšeslav; Ubar, Raimund-Johannes Proc. III International Conference "Distance Learning - Educational Sphere of XXI Century" : Minsk, Belorussia, 2003 2003 / p. 336-342

Elmet Orasson tabab laskesporti

Orasson, Elmet Mente et Manu 2014 / lk. 18-19 : fot https://www.ester.ee/record=b1242496*est

Fast test cost calculation for hybrid BIST in digital systems

Orasson, Elmet; Raidma, Rein; Ubar, Raimund-Johannes; Jervan, Gert; Peng, Zebo Euromicro Symposium on Digital Systems Design : [Architectures, Methods and Tools : DSD 2001] : September 4-6, 2001, Warsaw, Poland : proceedings 2001 / p. 318-325 : ill <https://www.semanticscholar.org/paper/Fast-test-cost-calculation-for-hybrid-BIST-in-Orasson-Raidma/5aafcd5a18c2aabf0ad20cac10af10727f3c58f>

Fault collapsing in digital circuits using fast fault dominance and equivalence analysis with SSBDs

Ubar, Raimund-Johannes; Jürimägi, Lembit; Orasson, Elmet; Raik, Jaan VLSI-SoC : Design for Reliability, Security, and Low Power : 23rd IFIP WG 10.5/IEEE International Conference on Very Large Scale Integration, VLSI-SoC 2015 Daejeon, Korea, October 5-7, 2015 : revised selected papers 2016 / p. 23-45 : ill https://doi.org/10.1007/978-3-319-46097-0_2 [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Functional built-in self-test for processor cores in SoC

Ubar, Raimund-Johannes; Indus, Viljar; Kalmend, Oliver; Evertson, Teet; Orasson, Elmet 30th IEEE NORCHIP Conference : Copenhagen, Denmark, November 12-14, 2012 2012 / p. 1-4 : ill <https://ieeexplore.ieee.org/document/6403148>

Graphical user interface for Turbo Tester toolset

Orasson, Elmet BEC 2004 : Baltic Electronics Conference : Post-Graduate Student Session : Tallinn University of Technology, October 3-6, 2004, Tallinn, Estonia 2004 / p. 12 : ill

Hybrid BIST optimization using reseeding and test set compaction

Jervan, Gert; Orasson, Elmet; Kruus, Helena; Ubar, Raimund-Johannes Microprocessors and microsystems 2008 / 5/6, p. 254-262 : ill <https://www.sciencedirect.com/science/article/abs/pii/S0141933108000288>

Hybrid BIST optimization using reseeding and test set compaction

Jervan, Gert; Orasson, Elmet; Kruus, Helena; Ubar, Raimund-Johannes 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 596-603 : ill
<http://dx.doi.org/10.1109/DSD.2007.4341529>

Hybrid built-in self-test : methods and tools for analysis and optimization of BIST = Sisseehitatud hübriidne isetestimine : meetodid ja vahendid analüüsiks ning optimeerimiseks
Orasson, Elmet 2007 https://www.ester.ee/record=b2305436*est

HyFBIST : hybrid functional built-in self-test in microprogrammed data-paths of digital systems

Ubar, Raimund-Johannes; Mazurova, Natalja; Smahtina, Julia; Orasson, Elmet; Raik, Jaan Proceedings of the 11th International Conference : Mixed Design of Integrated Circuits and Systems : MIXDES 2004 : Szczecin, Poland, 24-26 June 2004 2004 / p. 497-502 : ill

Interactive teaching software "Introduction to digital test"

Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich; Orasson, Elmet 45. Internationales Wissenschaftliches Kolloquium, 04.-06.10.2000 : Tagungsband 2000 / S. 949-954

Internet-based software for teaching test of digital circuits

Ubar, Raimund-Johannes; Orasson, Elmet; Wuttke, Heinz-Dietrich 23rd International Conference on Microelectronics : MIEL 2002, Niš, Yugoslavia, 12-15 May 2002 : proceedings. Volume 2 2002 / p. 659-662 : ill <https://ieeexplore.ieee.org/document/1003344>

Internet-based software for teaching test of digital circuits

Ubar, Raimund-Johannes; Jutman, Artur; Orasson, Elmet; Raik, Jaan; Evertson, Teet; Wuttke, Heinz-Dietrich Microelectronics education : proceedings of the 4th European Workshop on Microelectronics Education : EWME 2002, Spain, May 23-24, 2002 2002 / p. 317-320 : ill <https://ieeexplore.ieee.org/document/1003344>

Investigating defects in digital circuits by Boolean differential equations

Kruus, Helena; Orasson, Elmet; Robal, Tarmo; Ubar, Raimund-Johannes The 4th International Conference "Distance Learning - Educational Sphere of XXI Century" (DLESC'04) 2004 / p. 432-435

Java applet for self-learning of digital test issues [Electronic resource]

Ubar, Raimund-Johannes; Orasson, Elmet; Evertson, Teet 13th EAEEIE Annual Conference, 8th-10th April, 2002, York, England 2002 / [4] p. [CD-ROM]

Learning digital test and diagnostics via internet

Ubar, Raimund-Johannes; Jutman, Artur; Kruus, Margus; Orasson, Elmet; Devadze, Sergei; Wuttke, Heinz-Dietrich International journal of online engineering 2007 / 1, [9] p. : ill https://www.db-thueringen.de/servlets/MCRFileNodeServlet/dbt_derivate_00032681/iJOE_1681-1221_03_2007_1_361.pdf

Learning digital test and diagnostics via internet [Electronic resource]

Ubar, Raimund-Johannes; Jutman, Artur; Kruus, Margus; Orasson, Elmet; Devadze, Sergei; Wuttke, Heinz-Dietrich International journal of computing & information sciences 2006 / 2, p. 86-96 : ill

Optimization of memory-constrained hybrid BIST for testing core-based systems

Jervan, Gert; Kruus, Helena; Orasson, Elmet; Ubar, Raimund-Johannes Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK teise aastakonverentsi artiklite kogumik : 11.-12. mai 2007, Viinistu kunstimuseum 2007 / lk. 133-136 : ill

Optimization of memory-constrained hybrid BIST for testing core-based systems

Jervan, Gert; Kruus, Helena; Orasson, Elmet; Ubar, Raimund-Johannes Proceedings of the IEEE 2nd International Symposium on Industrial Embedded Systems : SIES'2007 : Lisbon, Portugal, 4-6 July 2007 2007 / p. 71-77
<https://ieeexplore.ieee.org/document/4297319>

Optimization of the store-and-generate based built-in self-test

Ubar, Raimund-Johannes; Jervan, Gert; Kruus, Helena; Orasson, Elmet; Aleksejev, Igor BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 199-202 : ill

Research environment for teaching digital test

lvask, Eero; Jutman, Artur; Orasson, Elmet; Raik, Jaan; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich Synergies between Information and Automation : 49. Internationales Wissenschaftliches Kolloquium, 27.-30.9.2004, Technische Universität Ilmenau, Germany. Volume 2 2004 / p. 468-473 : ill https://pld.ttu.ee/dildis/publications/IWK'2004_res_inv.pdf

Scalable algorithm for structural fault collapsing in digital circuits

Ubar, Raimund-Johannes; Jürimägi, Lembit; Orasson, Elmet; Raik, Jaan 2015 IFIP/IEEE International Conference on Very Large Scale Integration (VLSI-SoC) : October 5-7, 2015, Daejeon, Korea 2015 / p. 171-176 : ill

Self-learning tool for digital test

Ubar, Raimund-Johannes; Orasson, Elmet; Evartson, Teet Proceedings of 2nd International Conference "Distance Learning - Educational Sphere of the XXI Century" 2002 / p. 36-38 : ill

Sequential circuits BIST with status bit control

Raik, Jaan; Orasson, Elmet; Ubar, Raimund-Johannes Proceedings of the 11th International Conference : Mixed Design of Integrated Circuits and Systems : MIXDES 2004 : Szczecin, Poland, 24-26 June 2004 2004 / p. 507-510 : ill
https://pld.ttu.ee/~raiub/files/aaaaa_pulk/MIXDES/jaan.pdf

Teaching advanced test issues in digital electronics

Ubar, Raimund-Johannes; Orasson, Elmet; Raik, Jaan; Wuttke, Heinz-Dietrich Proceedings of the 6th IEEE International Conference on Information Technology Based Higher Education and Training : ITHET : July 7-9, 2005, Juan Dolio, Dominican Republic 2005 / p. S2B-1 - S2B-6 : ill <http://dx.doi.org/10.1109/ITHET.2005.1560318>

Teaching diagnostic modeling of digital systems with decision diagrams [Electronic resource]

Ubar, Raimund-Johannes; Raik, Jaan; Mironov, Dmitri; Evartson, Teet; Orasson, Elmet; Aarna, Margit; Wuttke, Heinz-Dietrich Proceedings of 12th IASTED International Conference on Computers and Advanced Technology in Education - CATE 2009 : St. Thomas, US, November 22-24, 2009 2009 / p. 1-6. [CD-ROM]

A tool for teaching hierarchical fault diagnosis in digital circuits

Ubar, Raimund-Johannes; Kostin, Sergei; Orasson, Elmet; Evartson, Teet; Brik, Marina Proceedings of 9th European Workshop on Microelectronics Education – EWME'12 : Grenoble, France, May 9-11, 2012 2012 / p. 1-4

A tool set for teaching design-for-testability of digital circuits

Kostin, Sergei; Orasson, Elmet; Ubar, Raimund-Johannes EWME 2016 : 11th European Workshop on Microelectronics Education : May 11-13, 2016, Southampton, UK 2016 / [6] p. : ill <https://doi.org/10.1109/EWME.2016.7496466>

Turbo tester - diagnostic package for research and training

Aarna, Margit; Ivask, Eero; Jutman, Artur; Orasson, Elmet; Raik, Jaan; Ubar, Raimund-Johannes; Vislogubov, Vladislav; Wuttke, Heinz-Dietrich Radioelectronics and informatics 2003 / p. 69-73 : ill

WebTT - digitaalskeemide testimine ja diagnostikaalaste õppelaborite e-keskkond : [TTÜ arvutitehnika instituut esitles e-Ülikooli konverentsil kolme õppetöös kasutatavat süsteemi]

Robal, Tarmo; Orasson, Elmet Mente et Manu 2005 / 5. mai, lk. 5 : fot https://www.ester.ee/record=b1242496*est